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*MECA0010 – Reliability and stochastic modeling of engineered systems*

## Reliability: introduction and homogeneous Poisson process

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- Motivation.
  
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- **Reliability of engineered systems** and its evolution through time.
  
- Significance to engineering:
  - ◆ performance,
  
  - ◆ maintenance,
  
  - ◆ qualification and certification,
  
  - ◆ warranty,
  
  - ◆ ...
  
- Focus here on **statistical inferences of reliability characteristics from data** (as opposed to physical modeling of failure mechanisms and degradation).

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## Indicators of reliability

- We distinguish between non-repairable and repairable systems:
  - ◆ A **non-repairable system** is a system for which after failure, the only option is to replace the entire system with a new one.
  - ◆ A **repairable system** is a system which, after failure, can be restored to an operative condition by a maintenance action other than replacement of the entire system. Replacing the entire system by a new one may be an option, but it is not the only one.
  
- We will assume that the description of the system state at any time is reduced to two categories: **operative** and **failed**.
  
- As a model of the evolving system state, we consider a stochastic process  $\{X(t), t \in \mathbb{R}^+\}$  that is
  - ◆ indexed by time  $t$ ,
  - ◆ with values in a finite set of states  $\mathcal{E}$ ,
  - ◆ with  $\mathcal{E} = \mathcal{M} \cup \mathcal{P}$  with  $\mathcal{M} \cap \mathcal{P} = \emptyset$ ,
  - ◆ where  $\mathcal{M}$  is the finite set of operative states,
  - ◆ and  $\mathcal{P}$  is the finite set of failed states.

- **(Instantaneous) availability:**

$$d(t) = P(X(t) \in \mathcal{M}),$$

the probability that the system is operative at a given time.

- **Reliability:**

$$\tau(t) = P(\forall s \in [0, t] : X(s) \in \mathcal{M}),$$

the probability that the system is operative over the entire interval  $[0, t]$ .

- **Lifetime = time to failure:**

$$T = \inf \{s \geq 0 : X(s) \in \mathcal{P}\},$$

where we have the property  $\tau(t) = P(T > t)$ .

- **Mean time to failure:**

$$\text{mttf} = E\{T\}.$$

- **Relationship between mean time to failure and reliability:**

$$\begin{aligned} \text{mttf} = E\{T\} &= \int_{\mathbb{R}_0^+} t \rho_T(t) dt = [t(c_T(t) - 1)]_0^{+\infty} - \int_{\mathbb{R}_0^+} (c_T(t) - 1) dt \\ &= \int_{\mathbb{R}_0^+} (1 - c_T(t)) dt = \int_{\mathbb{R}_0^+} P(T > t) dt = \int_{\mathbb{R}_0^+} \tau(t) dt. \end{aligned}$$

- (Instantaneous) availability.

- Reliability.

- First time to failure.

- **Maintainability:**

$$m(t) = P(\exists s \in [0, t], X(s) \in \mathcal{M} | X(0) \in \mathcal{P}),$$

the probability that the repair of the system is completed before the time  $t$  given that the system was in a failed state at the initial time instant.

- **Mean time to repair:**

$$\text{mttr} = E\left\{ \inf \{s \geq 0 : X(s) \in \mathcal{M} | X(0) \in \mathcal{P}\} \right\}.$$

## ■ Rate of occurrence of failures:

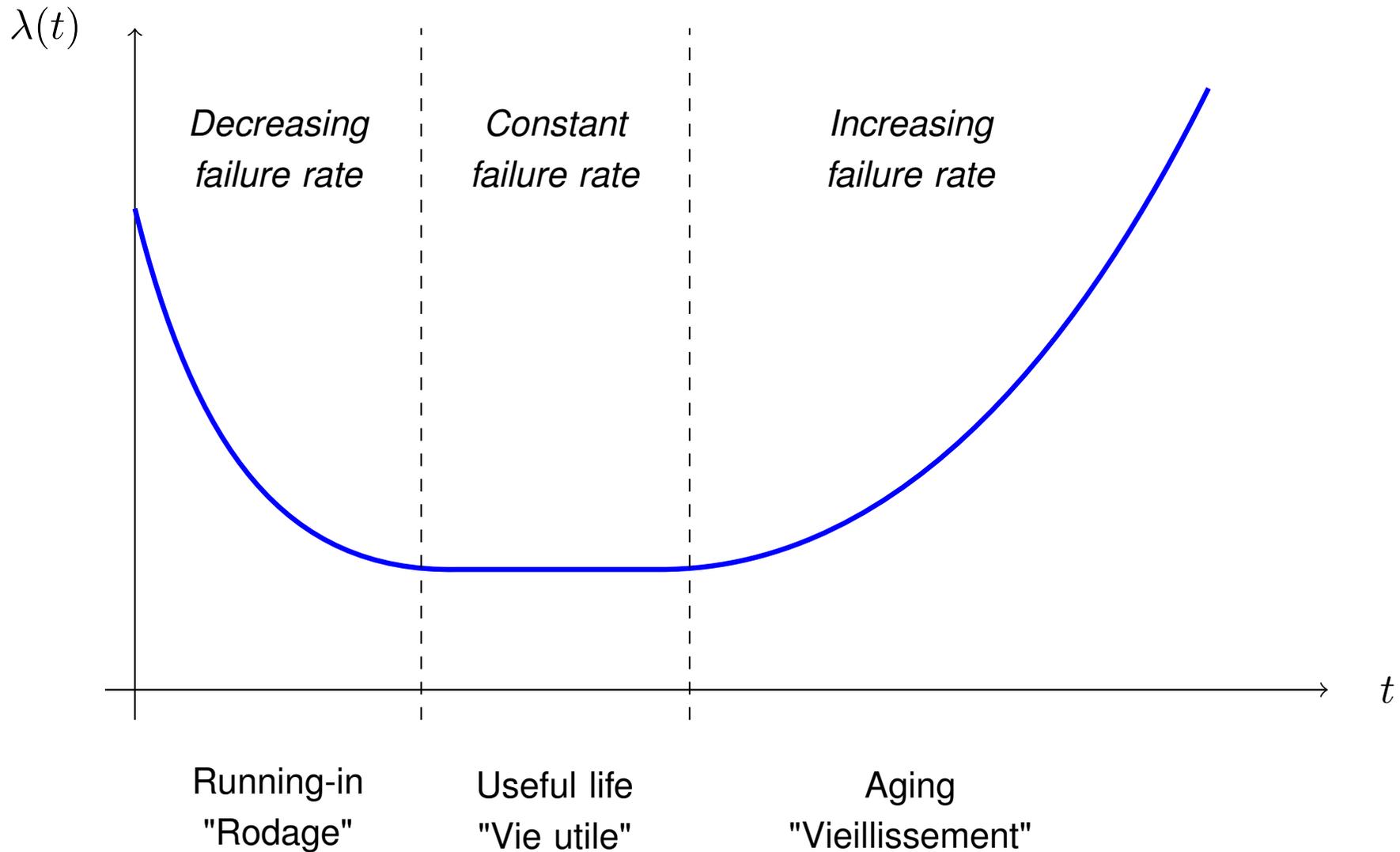
$$\lambda(t) = \begin{cases} \frac{\rho_T(t)}{1 - c_T(t)} & \text{if } 1 - c_T(t) \neq 0, \\ 0 & \text{if } 1 - c_T(t) = 0. \end{cases}$$

## ■ Interpretation as a rate:

$$\begin{aligned} \lambda(t) &= \lim_{\Delta t \rightarrow 0} \frac{1}{\Delta t} P(t \leq T \leq t + \Delta t | T > t) \\ &= \lim_{\Delta t \rightarrow 0} \frac{1}{\Delta t} \frac{P(t < T \leq t + \Delta t)}{P(T > t)} \\ &= \lim_{\Delta t \rightarrow 0} \frac{1}{\Delta t} \frac{c_T(t + \Delta t) - c_T(t)}{1 - c_T(t)} \\ &= \frac{\rho_T(t)}{1 - c_T(t)}. \end{aligned}$$

# Rate of occurrence of failures

## ■ Bathtub curve ("courbe en baignoire"):



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## Models for minimal repair

- To model the system evolution, it is essential to describe the characteristics of the system after maintenance.
- Many repairs in industry do not return a system to a state "as good as new" but rather result in reliability characteristics that are basically the same as they were just before the failure occurred, that is, the repaired system is **"as good as old"**. In other words, the **"age" of the system after repair is the same as it was before failure**.
- This behavior frequently arises in the maintenance of complex systems for which after failure, only small parts of the system are replaced by new ones.
- We assume that the **time to repair is negligible** (compared to the time of failure).

# Counting and point processes

- The reliability of a repairable system that undergoes **"minimal" repairs** that restore the system to a state "as good as old" after failure and for which the **time to repair is negligible** can be described in different ways, such as by describing the **number of failures suffered by the system up to a given time  $t$** , by means of the **lengths of time between consecutive failures**, and so forth.

- **Counting process:**

$$\{N(t), t \geq 0\},$$

where  $N(t)$  is the number of failures suffered by the system in the interval  $[0, t]$ , with  $N(0) = 0$ .

- We assume that the **time to repair is negligible** (compared to the time of failure).

- **Point process:**

$$\{T_n, n \geq 1\},$$

which collects the time instants at which the system suffers failures.

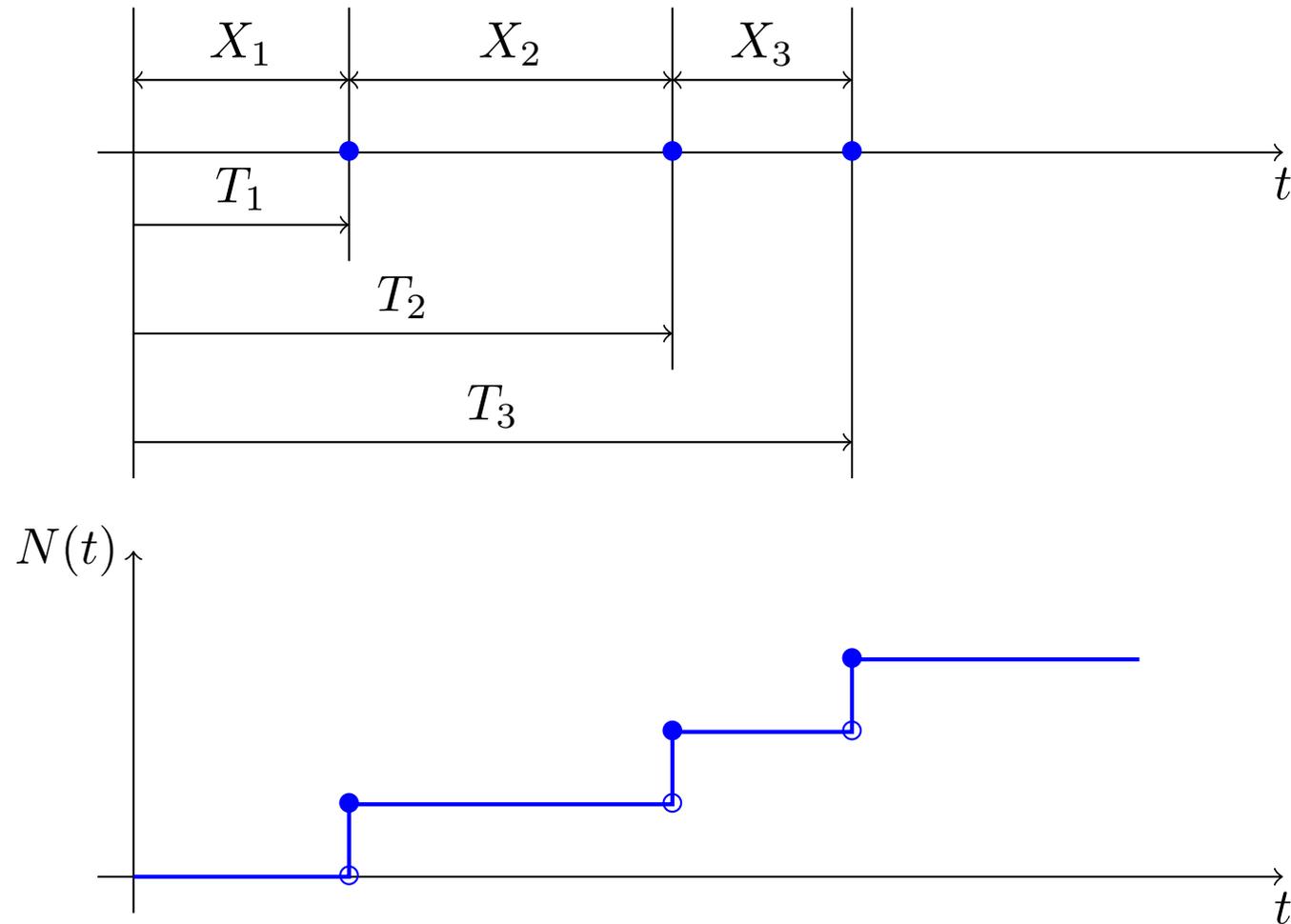
- **Lengths of time between consecutive failures:**

$$\{X_n, n \geq 1\},$$

with  $X_1 = T_1$  and  $X_n = T_n - T_{n-1}$  for  $n \geq 2$ .

# Counting and point processes

- Counting process  $\{N(t), t \geq 0\}$ :



- A stochastic process  $\{N(t), t \geq 0\}$  indexed by  $\mathbb{R}^+$  with values in  $\mathbb{N}$  is a **Poisson process** with mean function  $m$ , where  $t \mapsto m(t)$  is an increasing and positive function, if and only if
  - ◆  $\{N(t), t \geq 0\}$  has **independent increments**, that is, for any  $0 \leq s < t \leq u < v < +\infty$ , the random variables  $N(v) - N(u)$  and  $N(t) - N(s)$  are statistically independent.
  - ◆  **$N(0) = 0$ .**
  - ◆ for any  $0 \leq s < t$ ,  $N(t) - N(s)$  is a r.v. with **Poisson distribution** with mean  $m(t) - m(s)$ :

$$P\{N(t) - N(s) = n\} = \frac{(m(t) - m(s))^n}{n!} \exp\left(- (m(t) - m(s))\right).$$

# Homogeneous Poisson process

- The Poisson process  $\{N(t), t \geq 0\}$  is **homogeneous** if the mean function  $m$  is of the form  $m(t) = \lambda t$  with  $\lambda$  a positive constant, that is, if the average of the number of failures occurring increases linearly with the time interval under consideration.
- Let  $\{N(t), t \geq 0\}$  be a homogeneous Poisson process with parameter  $\lambda$ . Then, the **first time to failure obeys an exponential distribution with parameter  $\lambda$** .

Proof:

$$\lim_{h \rightarrow 0} \frac{P(0 < t_1 \leq T_1 < t_1 + h)}{h} = \lim_{h \rightarrow 0} \frac{\frac{(\lambda t_1)^0}{0!} \exp(-\lambda t_1)}{h} \frac{\frac{(\lambda h)^1}{1!} \exp(-\lambda h)}{h} = \lambda \exp(-\lambda t_1).$$

# Homogeneous Poisson process

- More generally, let  $\{N(t), t \geq 0\}$  be a homogeneous Poisson process with parameter  $\lambda$ , then the **lengths of time between consecutive failures  $\{X_n, n \geq 1\}$  are statistically independent and identically distributed with exponential distribution with parameter  $\lambda$ .**

- **Link with rate of occurrence of failures:**

$$\frac{\rho_T(t)}{1 - c_T(t)} = \frac{\lambda \exp(-\lambda t)}{\exp(-\lambda t)} = \lambda.$$

Homogeneous Poisson process  $\equiv$  no aging.

# Homogeneous Poisson process

- Let  $\{N(t), t \geq 0\}$  be a homogeneous Poisson process with parameter  $\lambda$ . Then, the probability distribution of the instants at which the system suffers its first  $n$  failures admits as a density

$$\rho_{(T_1, \dots, T_n)}(t_1, \dots, t_n) = \lambda^n \exp(-\lambda t_n) \mathbf{1}(0 < t_1 < \dots < t_n),$$

and the probability distribution of these instants given that  $\{N(t) = n\}$  admits as a density

$$\rho_{(T_1, \dots, T_n | N(t))}(t_1, \dots, t_n | n) = \frac{n!}{t^n} \mathbf{1}(0 < t_1 < \dots < t_n < t).$$

Proof:

$$\begin{aligned} \rho_{(T_1, \dots, T_n)}(t_1, \dots, t_n) &= \lambda \exp(-\lambda t_1) \times \dots \times \lambda \exp(-\lambda(t_n - t_{n-1})) \times \mathbf{1}(0 < t_1 < \dots < t_n) \\ &= \lambda^n \exp(-\lambda t_n) \mathbf{1}(0 < t_1 < \dots < t_n). \end{aligned}$$

# Homogeneous Poisson process

Proof (continued):

$$\begin{aligned} & \rho_{(T_1, \dots, T_n | N(t))} (t_1, \dots, t_n | n) \\ &= c \lambda^{n+1} \exp(-\lambda t_{n+1}) \mathbf{1}(0 < t_1 < \dots < t_n < t < t_{n+1}) \\ &= \int_t^{+\infty} c \lambda^{n+1} \exp(-\lambda t_{n+1}) \mathbf{1}(0 < t_1 < \dots < t_n < t) dt_{n+1} \\ &= c \lambda^n \exp(-\lambda t) \mathbf{1}(0 < t_1 < \dots < t_n < t). \end{aligned}$$

Finally,

$$\begin{aligned} & \int_{\mathbb{R}^n} c \lambda^n \exp(-\lambda t) \mathbf{1}(0 < t_1 < \dots < t_n < t) dt_1 \dots dt_n = 1 \\ \Rightarrow & c = \frac{1}{\lambda^n \exp(-\lambda t)} \frac{n!}{t^n} \end{aligned}$$

since

$$\int_{\mathbb{R}^n} \mathbf{1}(0 < t_1 < \dots < t_n < t) dt_1 \dots dt_n = \frac{n!}{t^n}.$$

## Suggested reading material

- L. Wehenkel. *Eléments de statistiques*. Université de Liège. Lecture notes.

## Additional references also consulted to prepare this lecture

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- D. Foata and A. Fuchs. *Processus stochastiques: processus de Poisson, chaînes de Markov et martingales*. Dunod, 2004.
- H. Procaccia, E. Fertou, and M. Procaccia. *Fiabilité et maintenance des matériels industriels réparables et non réparables*. Lavoisier, 2011.
- C. Soize. *The Fokker–Planck equation for stochastic dynamical systems and its explicit steady state solutions*. World Scientific Publishing, 1994.